

# On-Line Testing Workshop (Ioltw 2002), 8th IEEE International

by IEEE Computer Society

Self-Checking FSM Design with Observing only FSM Outputs On-Line Testing Workshop (Ioltw 2002), 8th IEEE International: 9780769516424: Books - Amazon.ca. ?A. Ademaj, P. Grillinger, P. Herout, and J. Hlavicka, Fault tolerance 18 Feb 2002 . 8th IEEE International On-Line Testing Workshop. Hotel Delos - Isle of Bendor, France July 8-10, 2002. General Chair M. Nicolaidis, On-Line Testing Workshop (Ioltw 2002), 8th IEEE International . 2002. Proceedings of the Eighth IEEE International On-Line Testing Workshop (IOLTW 2002). 2001. Proceedings Seventh International On-Line Testing Automated synthesis of SEU tolerant architectures from oo . - Core Papers from a July 2002 conference are presented in sections on hardware fault tolerance, hardware-software design and validation of fault tolerant systems, . IOLTW 2002, Call For Participation . Duplicated Data (EDDD) approaches. Proceedings of the Eighth IEEE International On-Line Testing Workshop (IOLTW 02). 0-7695-1641-6/02 \$17.00 © 2002 On-Line Testing Workshop (IOLTW 2002): 8th IEEE . - Google Books Proceedings of the 6th IEEE International On-Line Testing Workshop (IOLTW) . Page: .08. Full text available: Publisher Site · Organizing Committee. Page: .09. On-Line Testing Workshop (IOLTW 2002): 8th IEEE . - Virgo Guest Editor of the journal "IEEE JETTA: Journal of Electronic Testing - Theory and . 2002. 0. 1. 2. 1. 0. 0. 0. 0. 0. 4. 2003. 0. 2. 1. 3. 1. 0. 0. 0. 0. 7. 2005. 0. 0. 2. 1 . 8th IEEE International Design and Test Symposium (IDT13), Marrakesh .. IEEE International On-Line Test Workshop (IOLTW 2001), Italy, July 2001, pp. Grid and Pervasive Computing: 8th International Conference, GPC . - Google Books Result 8th IEEE International On-Line Testing Workshop (IOLTW 2002), 8-10 July 2002, Isle of . 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IEEE Computer Society Staff; IEEE/IET Electronic Library (IEL) Proceedings of the Eighth IEEE International On-Line Testing . Proceedings of the Eighth IEEE International On-Line Testing Workshop (IOLTW 2002). Published in: On-Line Testing Workshop, 2002. 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